Docket No.

250386US2

# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Satoshi INABA, et al.

SERIAL NO: New Application

GAU:

FILED:

Herewith

**EXAMINER:** 

FOR:

SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD OF THE SAME

# INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

Applicant(s) wish to disclose the following information.

#### REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

### RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

#### CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

### **DEPOSIT ACCOUNT**

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

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Form PTO 1449		U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO.		SERIAL NO.		
(Modified)		PATENT AND TRAI	DEMARK OFFICE	250386US2		New Application		
				APPLICANT				
LIST OF REFERENCES CITED BY APPLICANT				Satoshi INABA, et al.				
N A				FILING DATE		GROUP		
				Herewith		(i)		
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	, NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE		
	AA	6,525,403	02/25/03	Satoshi INABA, et al.				
	AB							
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FOREIGN PATENT DOCUMENTS								
	DOCUMENT DATE			COUNTRY		TRANSLATION		
		NUMBER	DATE	COUNTRY		YES		NO
	AO	7-202146	08/04/95	Japan (with English Abstract)				x
	AP							
	AQ							
	AR							
	AS							
	AT							
	AU							
	AV		<u> </u>					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
Yang-Kyu CHOI, et al., "Sub-20nm CMOS FinFET Technologies", INTERNATIONAL ELECTRON DEVICES MEETING AW (IEDM) TECH. DIG., December 2001, pgs. 421-424								
	AX	Bin YU, et al., "FinFET Scaling to 10nm Gate Length", INTERNATIONAL ELECTRON DEVICES MEETING (IEDM) TECH. DIG., December 2002, pgs. 251-254						
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AZ						Additional References sheet(s) attached		
Examiner					Date Considered			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								